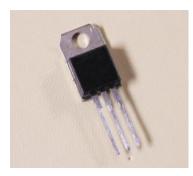
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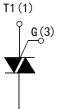
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JST20A / JST20B High Voltage TRIAC



NOTE:

IMAGE SERVES AS A VISUAL REPRESENTATION OF THE PRODUCT ONLY.



ABSTRACT

The JST20A/20B are high voltage TRIACs with high current density, SIPOS, and are glass passivated. These components are suitable for general purpose AC switching and can be used as an ON/OFF function in applications such as static relays, heating regulation, and so on. This design is specifically recommended for use on inductive loads.

FEATURES

- 2500V RMS isolation voltage from all three terminals to external heatsink
- I_{T(RMS)} = 20A
- V_{DRM}/V_{RRM} = 1200V
- V_{TM} = 1.65V

T2 (2) JST20E



JST20B(TO-220B:non-insulated) JST20A(TO-220A:insulated) UL file:E252906

ABSOLUTE MAXIMUM RATINGS

Parameter			Value	Unit	
Storage junction temperature range			-40 to +150	°C	
Operrating junction temperature range			-40 to +125	°C	
Repetitive Peak Off-state Voltage	Tj=25°C	VDRM	1200	v	
Repetitive Peak Reverse Voltage	Tj=25°C	VRRM	1200	V	
Non repetitive Surge Peak Off-state Voltage	tn=10mo Ti=25°C	Vdsm	1300	V	
Non repetitive Peak Reverse Voltage	tp=10ms,Tj=25°C	Vrsm	1300		
PMS on-state current (full sine wave)	JST20B Tc=88°C	T(RMS)	20	А	
RMS on-state current (full sine wave)	JST20A Tc=67°C		20		
Non repetitive surge peak on-state current	f=60Hz、t=16.7ms	тѕм	210	А	
(full cycle,Tj=25°C)	f=50Hz、t=20ms	1510	200		
I²t Value for fusing	tp=10ms	²t	200	A²s	
Critical rate of rise of on-state current IG=2×IG⊤, tr≤100 ns, f=120Hz, Tj=125°C			100	A/µs	
Peak gate current (tp=20us,Tj=125°C)			4	А	
Peak Gate Power Dissipation (tp=20us,Tj=125 °C)			10	W	
Average gate power dissipation (Tj=125°C)			1	W	

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ELECTRICAL CHARACTERISTICS					
Symbol	Test Condition	Quadrant		Limit	Unit
	Test Condition	Quadrant		BW	Unit
lgт	VD=12V RL=33Ω	1-11-111	MAX.	50	mA
Vgt	VD-12V RL-3302	1-11-111	MAX.	1.5	V
Vgd	VD=VDRM RL=3.3KΩ Tj =125℃	1-11-111	MIN.	0.2	V
IL	IG=1.2IGT	I-III	MAX.	90	mA
	13-1.2161	=	MAX.	120	mA
Ін	IT =100mA			75	mA
dV/dt	VD=67%VDRM gate open Tj=125℃		MIN.	500	V/µs
(dV/dt)c	(dI/dt)c=8.8A/ms Tj=125℃			12.5	V/µs

STATIC CHARACTERISTICS						
Symbol	Parameter		Value(MAX.)	Unit		
Vтм	I⊤м=28A,tp=380µs	T j= 25℃	1.65	V		
IDRM IRRM VD=VDRM VR=VRRM	T j=25 ℃	5	μΑ			
		T j= 125℃	2.5	mA		

THERMAL RESISTANCES					
Symbol	Parameter		Value	Unit	
Rth(J-C)	Junction to Case(AC)	JST20B	1.35	°C/W	
	Sufficient to Case(AC)	JST20A	2.15	C/VV	

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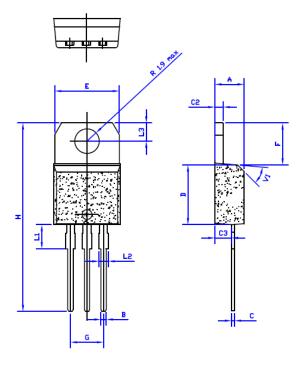
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DIMENSIONAL INFORMATION



	Dimensions						
Ref.	Millimeters			Inches			
	Min.	Тур.	Max.	Min.	Тур.	Max.	
А	4.4		4.6	0.173		1.181	
В	0.61		0.88	0.024		0.034	
С	0.46		0.70	0.018		0.027	
C2	1.23		1.32	0.048		0.051	
C3	2.4		2.72	0.094		0.107	
D	8.6		9.7	0.338		0.382	
E	9.8		10.4	0.386		0.409	
F	6.2		6.6	0.244		0.259	
G	4.8		5.4	0.189		0.213	
Н	28.0		29.8	11.0		11.7	
L1		3.75			0.147		
L2	1.14		1.7	0.044		0.066	
L3	2.65		2.95	0.104		0.116	
V1		40°			40°		

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FIG.1: Maximum power dissipation versus RMS on-state current(full cycle)

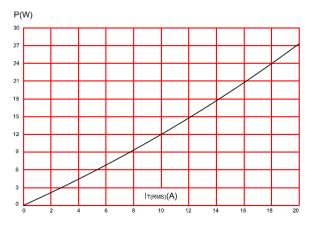
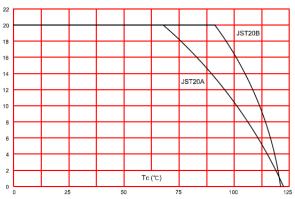


FIG.2: RMS on-state current versus case temperature(full cycle)

IT(RMS)(A)



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FIG.3:On-state characteristics (maximum values).

ITM(A) 100 Tjmax Vto=0.85V Rd=60mΩ 10 Tjmax Vto=1, 2, 3, 4, 5 FIG.4:Surge peak on-state current versus number of cycles.

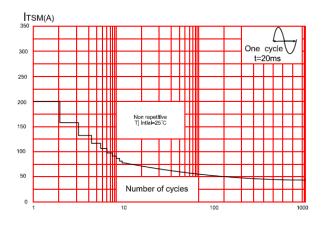


FIG.5:Non-repetitive surge peak on-state current for a sinusoidal pulse with width tp<10ms,and corresponding value of **I**²t.

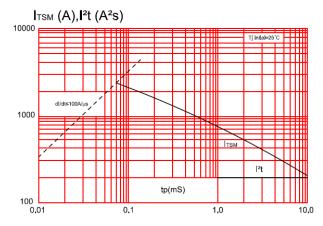
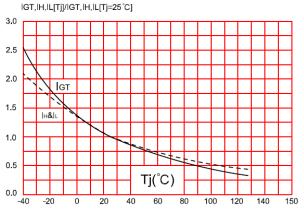


FIG.6:Relative variations of gate trigger current,holding current and latching current versus junction temperature(typical values)



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